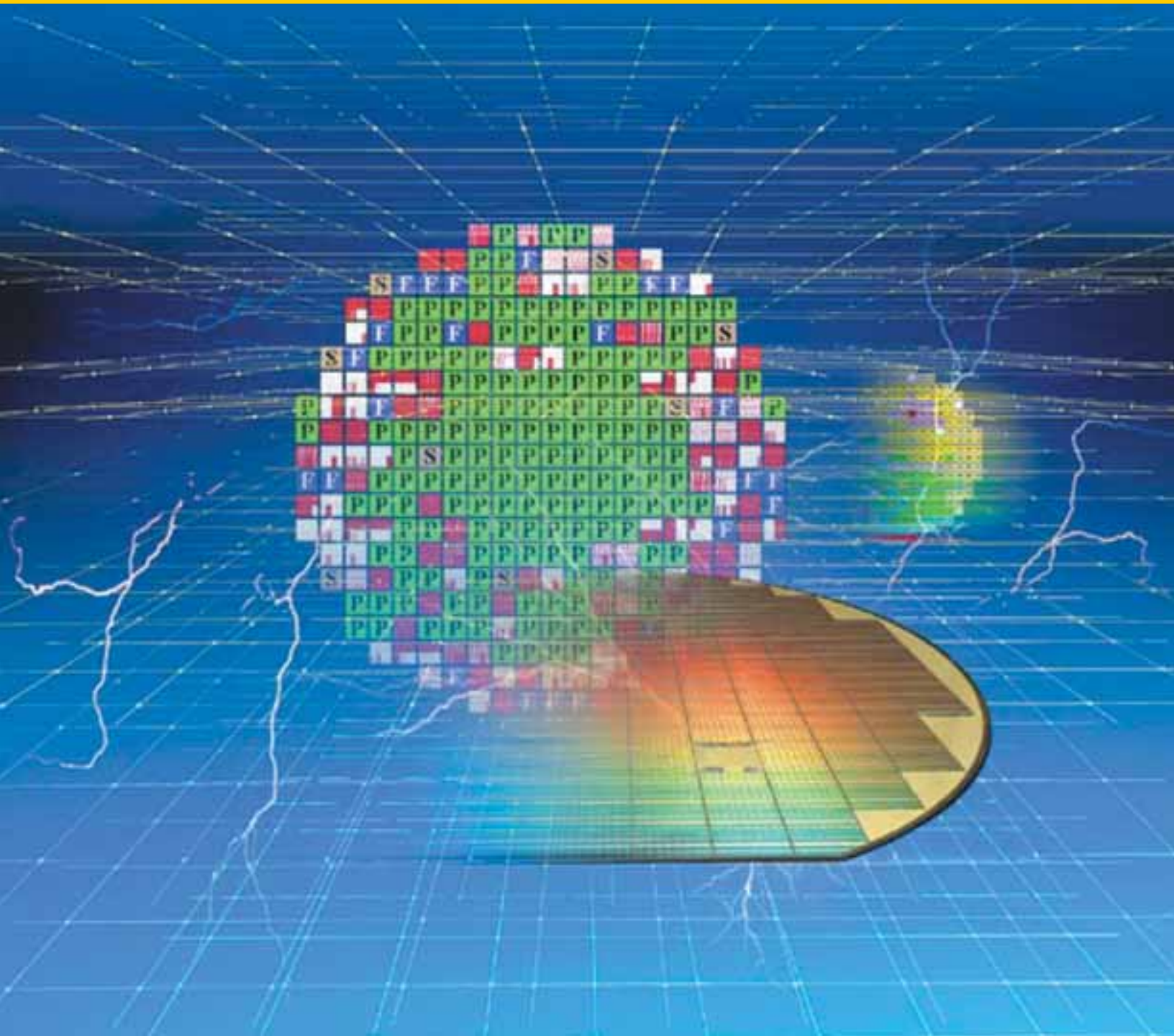


**ADVANTEST®**

**Wafer Failure Bit MAP 3**

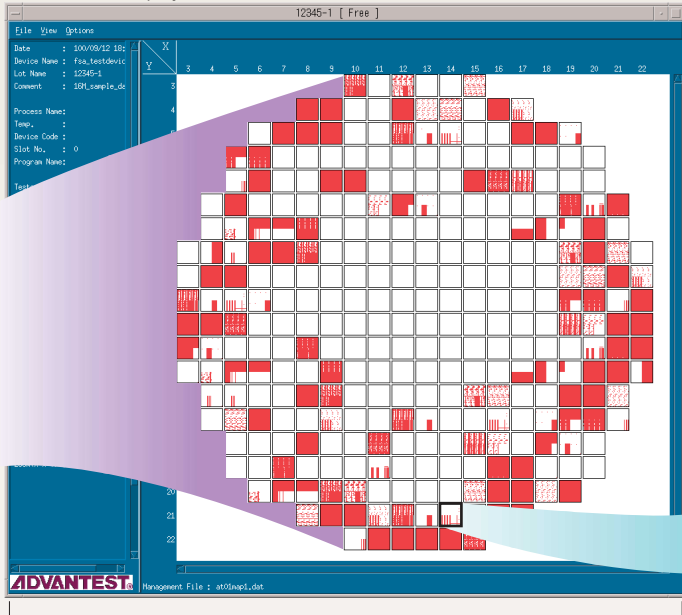
# WFBMAP3

**Wafer-scale Analysis of Fail Bits. Wide Support from Prototypes to Mass Production.**



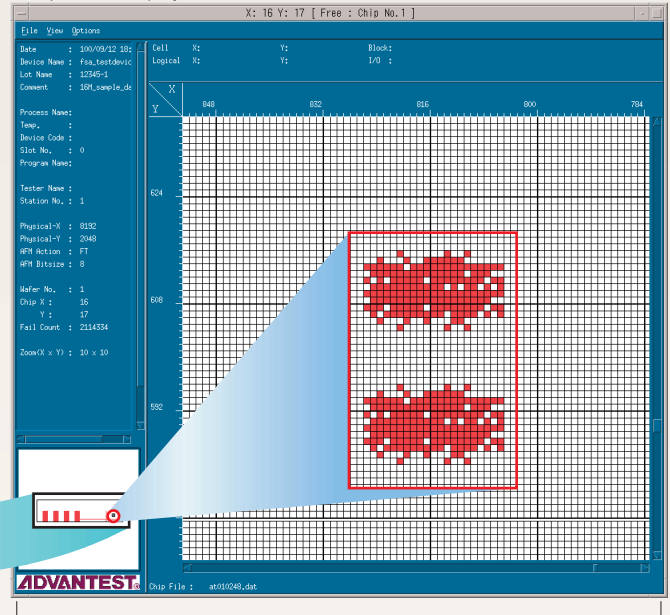


•Wafer-scale Display



Enables the inner surface tendency and intershot tendency to be viewed at a glance

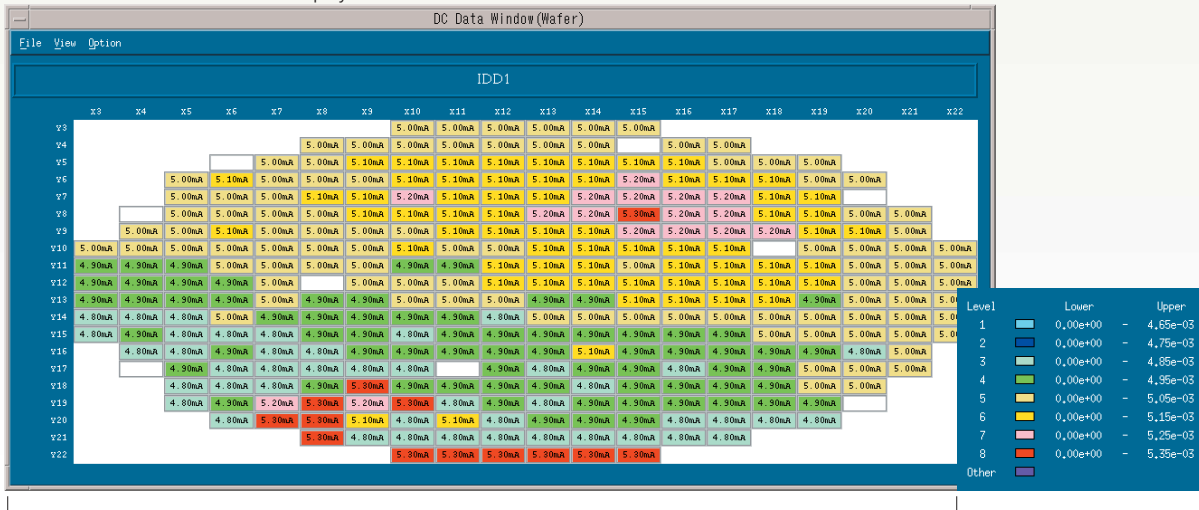
•Chip Zoom Display (with control window)



Can display zoomed image up to 1 cell.

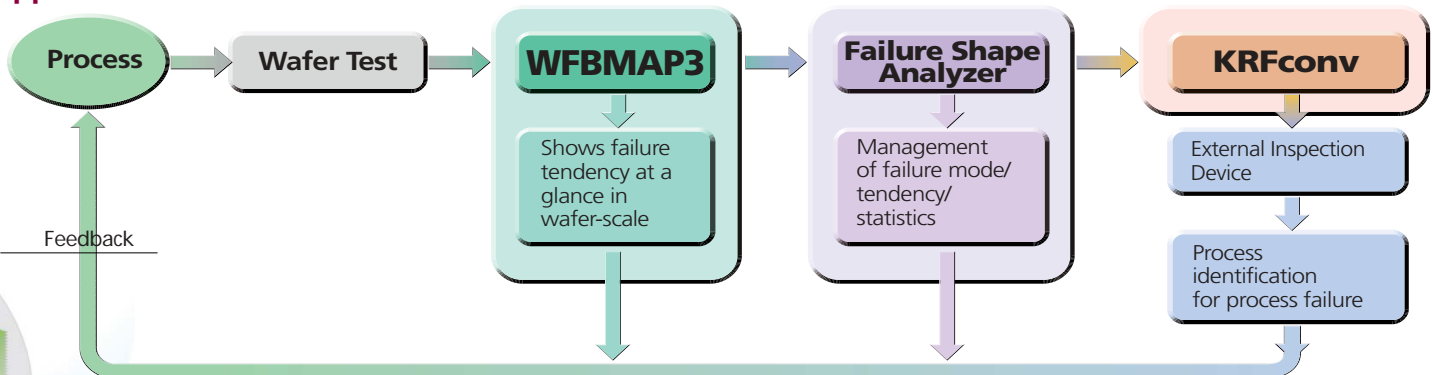
## DC Data Display Feature

•IDD1 measurement wafer-scale display



DC data measurement results can be color-coded and displayed in wafer-scale.

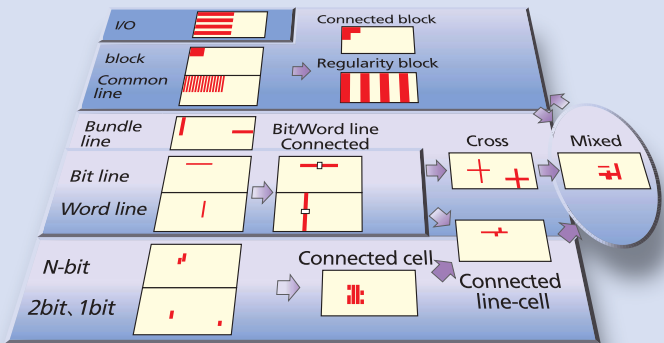
## Supports Yield Increase



WFBMAP3 Operating Environments / • Supported testers: T5371, T5375, T5500 series • Solaris 2.5.1 (Hardware 11/97), Solaris7 and above  
 WFBMAP3 Product Configuration / • WFBView (Display Tool) • WFBPhys (Physical Conversion Tool) • WFBRead (Data Read Tool) • WFBAccel (Accelerated Data Read Tool)  
 Related Software / • Failure Shape Analyzer • KRFconv KRF Converter Tool

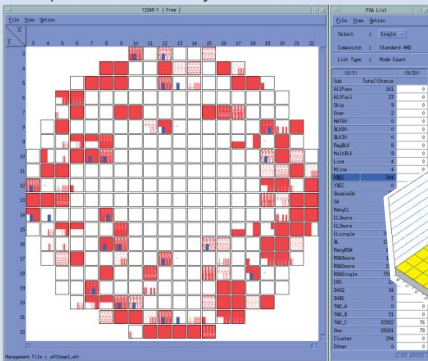
# Failure Shape Analyzer

This software tool automatically classifies failure mode according to memory device failure cause, and identifies the number and position of failures in each mode. By assigning numerical values to the failure status and processing these statistically, failure process hypothesis and identification can be conducted with ease, with the purpose of TAT reduction.



• Failure modes in which analysis is possible

## • Sample results of Analysis



• The example of 3D graphic display

- Failure mode definition that takes into account circuit configurations such as memory arrays and sense amps
- Through analysis sequence control features, analysis priority sequencing can be determined at will.
- Since analysis results can be exported to a CSV format file, statistical management is a snap using commercial spreadsheet software.
- The WFBMAP3 Link Feature provides solid support for failure analysis.

## Operating Environment

- Compatible Systems
  - Sun Ultra 1, 2, 5, 10, 30, 60, 80
  - Sun Enterprise 250, 450
- Solaris 2.5.1 (Hardware 11/97), Solaris7 and above
- Main Memory: 256 Mbytes and above
- Hard Disk: 8 Gbytes and above

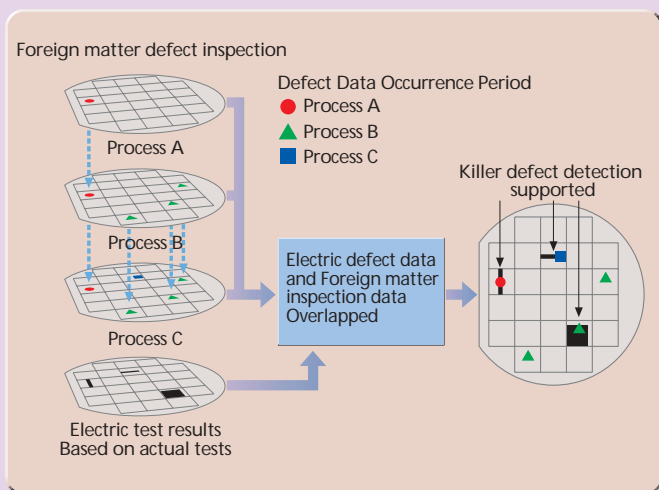
## Related Software

- WFBMAP3
- KRFconv

# KRFconv

## KLA Result Fail Converter

KRFconv is a software tool that converts Failure Shape Analyzer results as electric failure data into coordinates data that can be utilized in SEM and foreign matter defect equipments. The electronic failure data and foreign matter defect inspection equipment defect data is overlapped to determine with ease which defects in the process are killer defects, and achieve TAT reduction through speedy discovery of the problem process. discovery of the problem process.



- Conversion of Failure Shape Analyzer results to KRF (KLA Result File) version 1.1 and overlapping of electric failure data and foreign matter defect data are supported.
- Conversion feature for Failure Shape Analyzer failure mode to data readable by foreign matter inspection devices is enabled.
- Specific failure mode data conversion is enabled to allow pinpoint killer defect identification.
- Failure data from a specific chip in one wafer can be converted to enable pinpoint killer defect identification.
- Device definition for application with a wide variety of memory arrays is supported.

### Operating Environment

- Compatible Systems
  - Sun Ultra 1, 2, 5, 10, 30, 60, 80
  - Sun Enterprise 250, 450
- Solaris 2.5.1 (Hardware 11/97), Solaris7 and above
- Main Memory: 256 Mbytes and above
- Hard Disk: 8 Gbytes and above

### Related Software

- WFBMAP3
- Failure Shape Analyzer

\*Sun Ultra, Sun Enterprise, and Solaris are registered trademarks of Sun Microsystems Inc. in the US.

Please be sure to read the manual of product thoroughly before using the products.  
Specifications may change without notification.

**ADVANTEST CORPORATION**

Shinjuku-NS building, 4-1  
Nishi-Shinjuku 2-chome  
Shinjuku-ku, Tokyo 163-0880,  
Japan  
Tel: +81-3-3342-7500  
Fax: +81-3-5381-7661  
<http://www.advantest.co.jp>

**Advantest America, Inc**

3201 Scott Blvd., Santa Clara,  
CA 95054, U.S.A  
Tel: +1-408-988-7700  
Fax: +1-408-987-0691

**Advantest (Europe) GmbH**

Stefan-George-Ring 2,  
D-81929 Munich, Germany  
Tel: +49-89-99312-0  
Fax: +49-89-99312-101

**Advantest (Singapore) Pte. Ltd.**

438A Alexandra Road,  
#8-03/06 Alexandra Technopark  
Singapore 119967  
Tel: +65-274-3100  
Fax: +65-274-4055

**Advantest Taiwan, Inc.**

No.1 Alley 17, Lane 62,  
Chung-Ho Street, Chu-Pei City,  
Hsin Chu Hsien, Taiwan, R.O.C.  
Tel: +886-3-5532111  
Fax: +886-3-5541168

**Advantest Korea Co., Ltd.**

16F, MIRA EWASARAM Bldg.,  
942-1, Daechi-Dong,  
Kangnam-ku, #135-280, Seoul,  
Korea  
Tel: +82-2-3452-7157  
Fax: +82-2-3452-0370